

<b>Notice of References Cited</b>	Application/Control No. 10/563,238		Applicant(s)/Patent Under Reexamination UDA, MASAYUKI	
	Examiner Anastasia Midkiff		Art Unit 2882	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,751,287	06-2004	Kalyon et al.	378/71
*	B	US-4,916,720	04-1990	Yamamoto et al.	378/81
*	C	US-5,745,543	04-1998	De Bokx et al.	378/45
*	D	US-6,285,736	09-2001	Dosho, Akihide	378/79
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yellipreddi et al., Applications and Perspectives of a New Innovative XRF-XRD Spectrometer in Industrial Process Control, 2000, International Centre for Diffraction Data, Advances in X-ray Analysis, Vol. 42, Pp. 126-136.
	V	Rindby et al., Micro-Distribution of Heavy Elements in Highly Inhomogeneous Particles Generated from u-beam XRF/XRD Analysis, 1997, Nuclear Instruments and Methods in Physics Research B, Elsevier, Vol. 124, Pp. 591-604.
	W	Cornaby et al., An XRD/XRF Instrument for the Microanalysis of Rocks and Minerals, 2001, IOP Publishing, Measurement Science and Technology, Vol. 12, Pp. 676-683.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.